

10/23/2014



**RELIABILITY MONITOR REPORT  
FOR**

**San Antonio 0.8 $\mu$ m Silicon Gate (B8)**

**MAXIM INTEGRATED**

**160 RIO ROBLES  
SAN JOSE, CA 95134**

**This Report was prepared by  
MAXIM INTEGRATED Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX9788ETI+

The calculated failure rate for devices using this process is:

**FAILURE RATE: MTTF (YRS): 4651 QUANTITY: 48 FAILS: 0 FITS: 24.5**

The parameters used to calculate this failure rate are as follows:

**Cf: 60% Ea: 0.7 Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2013 and 9/30/2014 .

---

**Process Information:**

Process Description: San Antonio 0.8µm Silicon Gate (B8)

---

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1422	MAX9788ETI+	135°C	500 HRS	48	0	TALZBA066A
<b>Total:</b>						<b>0</b>	

---

**STORAGE LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1422	MAX9788ETI+	150°C	500 HRS	80	0	TALZBA066A
<b>Total:</b>						<b>0</b>	

---

**TEMPERATURE CYCLE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1422	MAX9788ETI+	-65C TO +150C (Condition C)	500 CYS	80	0	TALZBA066A
<b>Total:</b>						<b>0</b>	

**FAILURE RATE: MTTF (YRS): 4651 QUANTITY: 48 FAILS: 0 FITS: 24.5**